

Supporting Information  
for  
**Preparation and morphology-dependent wettability of porous  
alumina membranes**

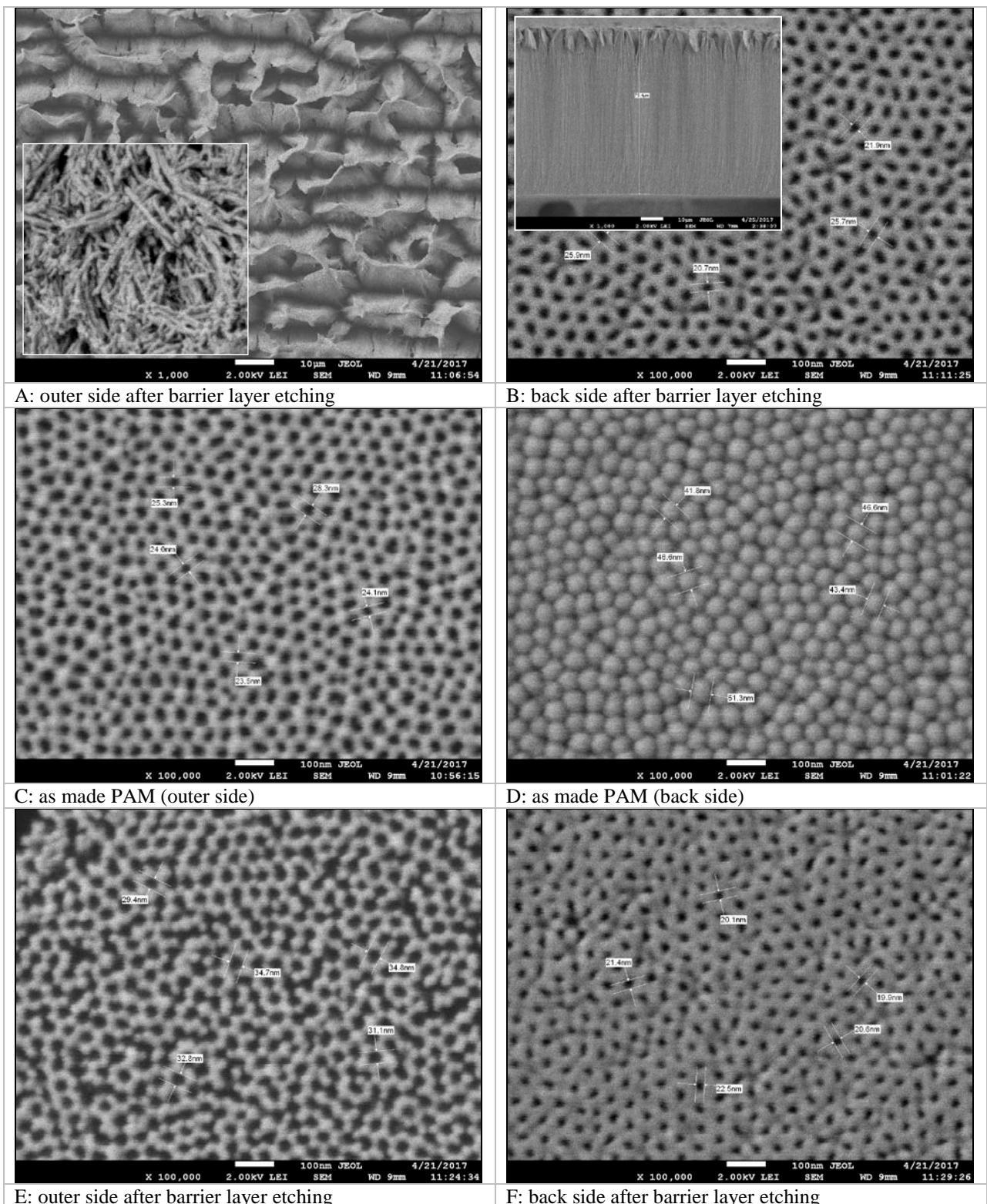
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**Additional experimental data**



**Figure S1:** SEM images of PAM (III) with size of 70 × 70 mm of 75 µm thickness before and after barrier layer etching.